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MAY 20 2004
PATENT & TRADEMARK OFFICE

Form PTO 1449 (Modified)		U. S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 251241US2	SERIAL NO. 10/812,887		
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Katsufumi EHATA					
		FILING DATE March 31, 2004		GROUP			
U. S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AA							
AB							
AC							
AD							
AE							
AF							
AG							
AH							
AI							
AJ							
AK							
AL							
AM							
AN							
none <i>Sm</i>							
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
<i>Sm</i>	AO	6-138076	05/20/1994	JAPAN	YES		X
<i>Sm</i>	AP			Reconsidered 2/30/06			
<i>Sm</i>	AQ						
<i>Sm</i>	AR						
<i>Sm</i>	AS						
<i>Sm</i>	AT						
<i>Sm</i>	AU						
<i>Sm</i>	AV			none <i>Sm</i>			
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>Sm</i>	AW	Y. IIJIMA, pages 20-23, "ELECTRONIC MONTHLY", 1998					
<i>Sm</i>	AX	JIS R 1627, Japanese Standards Association, pages 1-18, "TESTING METHOD FOR DIELECTRIC PROPERTIES OF FINE CERAMICS AT MICROWAVE FREQUENCY", July 1996					
<i>Sm</i>	AY	JIS R 1641, Japanese Standards Association, pages 1-29, "TESTING METHOD FOR DIELECTRIC PROPERTIES OF FINE CERAMIC PLATES AT MICROWAVE FREQUENCY", January 2002					
	AZ	<i>none</i>				<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>Jeff Matalini</i>				Date Considered 8/19/05			

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.